

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10551039	FUJITA ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
NIKHIL SRIRAMAN	3664	

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
700	245, 248, 249, 250, 253	12/20/2008	NS

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Consulted with Marc McDieunel	12/20/2008	
Assignee search on East, Inventor search on eDan		
NPL, including IEEE databases searched (see attached history)		
Reviewed submitted IDS references	7/12/2009	
Updated search in light of claim amendments; consulted with Examiner Jorge Peche and Examiner Kyung Kim on search strategy on claim interpretation	12/19/2009	
Consulted with Examiner Lin Olsen on apparatus claim construction in light of removal of "means plus function" language in Applicant's amendment	6/25/2010	
updated search, see attached EAST Search history	3/8/2011	JE
updated search, see attached EAST Search history	8/24/11	JE

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

/J. E/  
Examiner Art Unit 3664